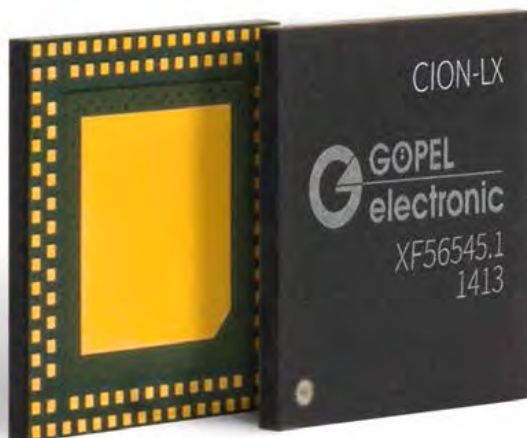




CION-LX

Next Generation of Configurable I/O Network Device



- world's first JTAG controllable mixed-signal Tester-on-Chip (ToC)
- support of latest Boundary Scan standards (IEEE1149.1/6/8.1)
- high flexible channel configuration for single-ended and differential signal transmission
- concurrent use of integrated analog and digital instruments
- support of dynamic at-speed functional tests
- integrated instruments available per channel
 - Arbitrary Waveform Generator
 - Analog Signal Recorder
 - Edge Detector
 - Frequency Meter
- well-suited for applications such as
 - design of advanced Boundary Scan I/O modules
 - design embedded signal monitoring
 - ATE pin electronics
- small footprint based on 116 pin LGA package

Parameters	Data
Technology	0.35 µm mixed-signal CMOS ASIC
Package	116 pin LGA (Landing Grid Array), 11 mm x 11 mm
Boundary Scan I/O	32 I/O (4 groups) 0.9-3.6 V, (maximum 24 mA @ 3.6V), IEEE 1149.1, IEEE 1149.8.1
High-current I/O	4 I/O (1 group) 0.9-2.0 V, (maximum 40 mA @ 2.0V), IEEE 1149.1, IEEE 1149.8.1
Differential I/O	8 (CML and LVDS support), IEEE 1149.1, IEEE 1149.6
ADC	12 bit with 400K sample/s and 1K memory (3.6 V max.)
DAC	10 bit with 1M sample/s and 1K memory (3.6 V max.)
Pull-up / pull-down	10 kOhm per channel programmable
TCK frequency (maximum)	100 MHz
Configuration of pin-properties	Single-ended: Driver Strength, pull-up pull-down Differential: CML, LVDS, Termination, Bias resistors
Integrated instruments	Arbitrary Waveform Generator (multiplexed), Signal Recorder (multiplexed), Edge Detection (per pin), Frequency Meter (multiplexed), Cycle Duration Measurement (multiplexed)
Operation modes	Pin Driver Mode, Bus Transceiver with registers and Tristate outputs, Boundary Scan Transceiver



CION-LX Evaluation Board enables evaluation of all CION-LX operation modes and features

Flexible test strategies

- mix of Boundary Scan with analog and digital at-speed functional test

CION-LX

New generation JTAG controllable Tester-on-Chip (ToC)

Better test quality

- higher test coverage and improved fault diagnostics

• Made in Germany